表面微結構化技術增進三五族半導體發光二極體

發光效率之研究

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摘 要

近年來,因三五族發光半導體能將注入之電能直接轉換成光輸出此一獨特之 材料特性能,發光二極體元件已被預測為下一世代之照明光源。然而,在高亮度 應用的需求上,現階段可見光波段的發光二極體元件與傳統照明光源相比較,其 發光效率還是不足。除此之外,在現今能源節約與環保意識抬頭的時代,更需要 精密設計發光二極體元件的結構,使其能更進一步提升發光效率,以達上述之需 求。

針對此點,本論文提出了一個新穎的結構能夠同時且有效地提升氮化銦鎵發 光二極體元件之內部量子效率與光淬取效率。

對於氮化銦鎵發光二極體元件來說,除了全內反射限制住光子被淬取的數目 之外,其發光效率主要的限制是來自於缺少適合成長此材料磊晶片的基板。也因 此,相當高密度的差排缺陷 (Dislocation defects) 會在發光二極體元件的活性層 中出現並減少電子電洞複合產生光子的機率,使得元件的發光效率降低。為了改 善這個問題,我們利用化學濕式蝕刻的方式來製作具有特定晶格斜面 (Facet) 圖 樣的藍寶石基板。我們發現將氮化銦鎵發光二極體元件成長在此特殊基板上將會 有效地提升元件之內部量子效率與光淬取效率。本論文將詳細地討論其主要的物 理機制—為何此結構能同時且有效地提升上述兩項重要的元件發光效率。

為了有效地解決螢光粉轉換效率與專利侵權這兩個普遍存在在現階段產業界 所製作的白光發光二極體元件上的問題,我們在本論文也提出利用並結合藍寶石

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基板剥離(Sapphire laser lift-off)與晶片接合技術(Wafer bonding)來製作互補色雙 波長(470-nm/550-nm)且無螢光粉參雜(Phosphor free)的白光發光二極體元件。在 電流的注入之下,此元件有著相當平坦與寬廣的電激發光譜結合著藍綠光的發射。此白光發光二極體元件的出光效率最高可達約一百二十流明每瓦。此白光發 光二極體元件有著相當高的潛力來促進固態照明時代的到來。



Research on Light Emission Enhancement of III-V Light-Emitting Diodes by Surface Modified Techniques

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Abstract

Light-emitting diodes (LEDs) are revolutionizing the world. Due to the unique characteristics of III-V compound semiconductor that provides the direct transfer of electrical energy into light, LEDs have been forecasted as lighting sources of next generation. However, efficiency of present state-of-the-art visible-spectrum LEDs are still low, as compared to that of conventional lighting sources specifically applied for high-flux utilization. In addition, since concerns of energy-conservation and environment-protection become emergent over the world, the desire for more sophisticated and high-efficiency LEDs structure's designs is even intense than ever.

In the first section of this thesis, we design a novel structure to simultaneously enhance both internal quantum efficiency and light extraction efficiency of InGaN-based LEDs.

For InGaN-based LEDs, in addition to the total internal reflection restricting photons extraction, the major difficulty is the lack of low-cost, single-crystal GaN to use as a growth substrate. Thus bunches of dislocation defects are normally observed inside active regions and served as nonradiative recombination centers. To alleviate these issues, we propose a novel structure of InGaN-based LEDs grown on chemical wet etching-patterned sapphire substrate (CWE-PSS) for simultaneously enhancing both internal quantum and light extraction efficiencies. The detail of physical mechanisms responsible for the dual enhancement in internal quantum efficiency and light extraction efficiency are also investigated in this thesis.

In the very end of this thesis, to alleviate the phosphor-convention issue commonly observed in conventional white light LEDs, phosphor-free InGaN-based dichromatic-color blue/green (470-nm/550-nm) LEDs are well designed and successfully fabricated by using sapphire laser lift-off (LLO) and wafer-bonding schemes. Flat and broad EL spectra with combination of blue and green colors are emitted, accompanying with the maximum luminous efficiency of 120lm/W. This integrated dichromatic lighting structure has a great potential to facilitate the early coming of solid-state lighting.



Acknowledgement

博士論文的順利完成,要感謝的人很多。首先要感謝的是辛苦指導我的王興 宗教授。從我碩士班開始,因為他悉心的指導,讓我習得專業知識與作科學研究 所應有的態度,而他那對於科學所抱持追根究底的精神,更是敦促我不斷研究的 動力來源。感謝郭浩中教授的耐心指導與教誨,提供專業的實務與經驗,使我習 得更深更廣的專業知識。感謝盧廷昌教授對論文提供的諸多寶貴建議與指導,讓 論文內容可以更加完善。感謝晶元光電研發中心徐大正博士與謝明勳博士,因為 他們的支持與栽培,我才得以順利完成博士學位。

同時我也要感謝壬色列理工學院物理系林尚佑教授提供我千里馬計畫擔任 訪問學者的機會,並對我非常照顧及對論文提供的諸多寶貴建議與指導;感謝口 試委員彭隆瀚老師、張振雄老師、張立老師、武東星老師、蘇炎坤老師對我論文 上的指導。

最後,感謝我親愛的家人,特別是感謝我的老婆惠君,總是默默的承受我 每個任性的決定並給我全力的支持,使我能忠於自己想追求的。

謝謝每位曾經幫助過我的朋友!

亞儒 于 96 年 11 月 29 日 交通大學光電所

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